

WHAT IS CLAIMED IS:

A vertical probe card having vertical probes for use in measurement of electric characteristics of the objects of measurement, comprising a main substrate forming conductive patterns, a plurality of probes drooping vertically from said main substrate, and a probe support provided at the back side of said main substrate for supporting said probes, wherein said probe support is disposed parallel to said main substrate, and has an upper guide plate and a lower guide plate for supporting the probes by passing the through-holes opened in each, and said lower guide plate is composed of a plurality of substrates laminated separably.